

In the United States Patent and Trademark Office

Appn. Number: _____

Appn. Filed: _____

Applicant(s): SYNOWICKI et al.

Appn. Title: METHOD OF DETERMINING BULK REFRACTIVE . . .

Examiner/GAU: _____ 1324

Mailed: With Application

At: _____

Information Disclosure Statement

Commissioner of Patents and Trademarks
Washington, District of Columbia 20231

Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references cited thereon.

Following are comments on these references pursuant to Rule 98:

THE FOLLOWING IDENTIFIED PATENTS ARE NOT ACCOMPANYING AS THEY WERE PREVIOUSLY IDENTIFIED AND ARE AVAILABLE IN THE FILE OF PARENT APPLICATION SERIAL NO. 10/407,578 Filed 04/07/03:

Published Patent Application No. US2002/0003665 A1 of Mearini et al., describes depositing Diamond Like Carbon (DLC) onto a roughened surface to cause it to become functionally smooth. While use of an Ellipsometer is contemplated to monitor the process, it is noted that DLC is not a flowable liquid as said terminology is used in the present invention, and nothing in said 665 Application suggests replacing the DLC with a flowable liquid. In particular, the DLC hardens and is not flowable after application of the methodology in the 665 Published Application.

Published Patent Application No. US2003/0025899 A1 of Amara et al., describes a method and apparatus for determining refractive index and thickness of thin films.

Patent No. 6,392,756 to Li et al., which describes method and apparatus for determining physical properties of thin films deposited on a complex substrate.

Patent No. 4,683,160 to Bloch et al., which describes solar cells with correlated roughness substrate.

Patent No. 5,910,842 to Piwonka-Corle et al., describes a focused beam ellipsometer.

Patent No. 6,444,898 to Fujisawa et al., describes a transparent layer product on a glass article.

Patents Nos. 5,502,560 and 5,610,708 to Anderson et al., which describe apparatus comprising a diffraction grating, and methodology of its use in determining concentrations of materials in liquids. An element comprising a diffraction grating is placed into contact with a sample and a beam of polarized light is caused to pass through said element and reflect from the interface between said diffraction grating and the sample. The reflected spectrum is reported to have features related to the complex dielectric constant, which is dependent on concentrations of materials in the sample.

Patents Nos. 5,307,105 and 5,420,680 to Isobe et al. describe apparatus and methodology for measuring refractive index and thickness of a thin film formed on a substrate.

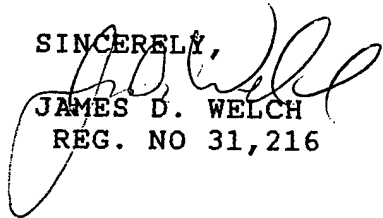
Patent No. 4,590,574 to Edmonds et al. describes a method for determining oxygen and carbon in a silicon substrate having a rough surface.

Patent No. 4,514,582 to Tiedje et al. describes a system which enhances optical absorption in amorphous silicon comprising a substrate with a sandblasted surface, upon which is deposited a thin film of semiconductor.

Patent No. 3,985,447 to Aspnes is disclosed as it describes measurement of thickness and refractive index of a thin film on a substrate.

Patent No. 3,973,994 to Redfield describes a solar cell comprising a thin layer of active semiconductor on the surface of a transparent substrate which has grooves present in the back side thereof.

SINCERELY,



JAMES D. WELCH
REG. NO 31,216

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination SYNOWICKI ET AL.	
	Examiner	Art Unit	Page 1 of 2

U.S. PATENT DOCUMENTS

U.S. PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,392,756 B1	05-2002	Li et al.	356/632
	B	US-2003/0025899 A1	02-2003	Amara et al.	356/128
	C	US-6,444,898 B1	09-2002	Fujisawa et al.	136/256
	D	US-2002/0003665 A1	01-2002	Mearini et al.	359/586
	E	US-5,910,842 A1	06-1999	Piwonka-Corle et al.	356/369
	F	US-4,683,160 A1	07-1987	Bloch et al.	428/141
	G	US-5,610,708	3-1997	Anderson et al.	356/128
	H	US-5,502,560	3-1996	Anderson et al.	356/128
	I	US-5,107,105	4-1992	Isobe et al.	250/225
	J	US-5,420,680	5-1995	Isobe et al.	365/128
	K	US-4,590,524	5-1986	Edmonds et al.	364/498
	L	US-4,514,582	4-1985	Tiedje et al.	136/256
	M	US-3,985,447	10-1976	Aspner	356/118

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
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	S				
	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Form PTO-1449 REV. 1-64 <div style="text-align: center;">U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</div> LIST OF PRIOR ART CITED BY APPLICANT <i>(Use several sheets if necessary)</i>	ATTY. DOCKET NO.	SERIAL NO.
	APPLICANT <u>Synowichi et al</u>	
	FILING DATE	GROUP

U.S. PATENT DOCUMENTS													
EXAMINER INITIAL		DOCUMENT NUMBER						DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA	3	9	7	3	9	9	4	8-1976	Redfield	136	89	
	AB												
	AC												
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EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.